

### **IEC QUALITY ASSESSMENT SYSTEM (IECQ)**

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

# Schedule of Scope to Certificate of Approval

## **Independent Testing Laboratory**

IECQ Certificate No.: IECQ-L JQAJP 13.0004
CB Certificate No.: JQA0012-001-T

Schedule Number: IECQ-L JQAJP 13.0004-S Rev No.: 8 Revision Date: 2019/11/01 Page 1 of 1

### **Type of Components**

TIC C 7 4 40 1000	T 1	· · · · · · · · · · · · · · · · · · ·	1	1 . 1	1
JIS C 5442:1996	LOW MONIOR OLD	ectromagnetic re	LOTTO TOP 11	ductrial agni	rol orrounts
11.7 ( )44/ 1770	LUW DUWELER	ECHOHIAVHENC IC	114 V S 1101 111	CHISHTAL CORR	TOT CITCHINS

IEC 61076-1:2006 Connectors for electronic equipment

IEC 60384-1:2016 Fixed capacitors for use in electronic equipment IEC 60115-1:2008 Fixed resistors for use in electronic equipment

#### **ENVIRONMENTAL TEST**

ELIT TILLOT (IVIE)	
IEC 60068-2-1:2007	Cold
IEC 60068-2-2:2007	Dry heat
IEC 60068-2-11:1981	Salt mist
IEC 60068-2-14:2009	Change of temperature
IEC 60068-2-30:2005	Damp heat, cyclic (12+12-hour cycle)
IEC 60068-2-38:2009	Composite temperature/humidity cyclic test
JIS C 60068-2-42:1993	Sulphur dioxide test for contacts and connections
JIS C 60068-2-43:1993	Hydrogen sulphide test for contacts and connections
JIS C 60068-2-52:2000	Salt mist, cyclic (sodium chloride solution)
IEC 60068-2-66:1995	Damp heat, steady state (unsaturated pessurized vapour)
IEC 60068-2-67:1995	Damp heat, steady state, accelerated test primarily
	intended for components
IEC 60068-2-78:2012	Damp heat, steady state



